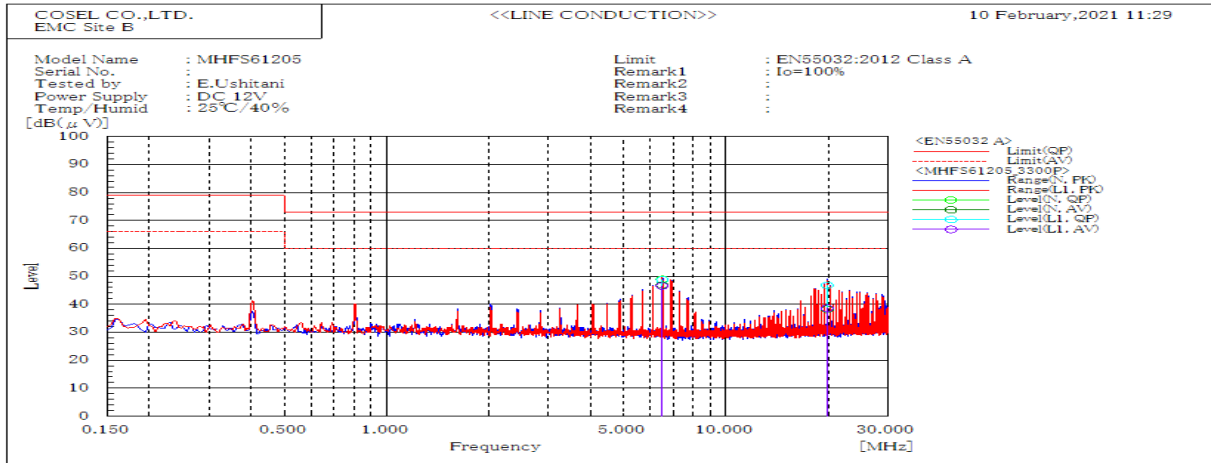
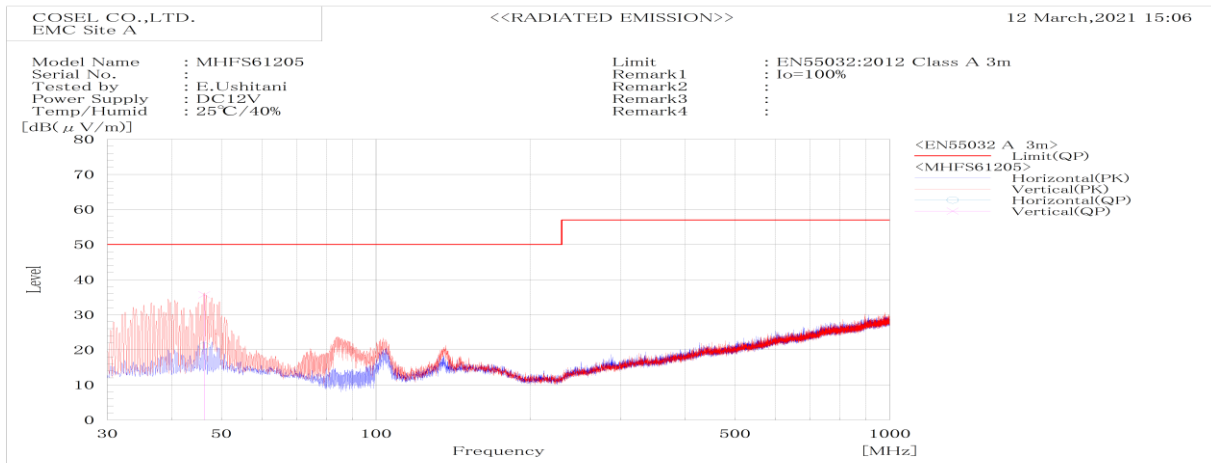


DATA SHEET		Date	05-Nov-21
Model	MHFS61205	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



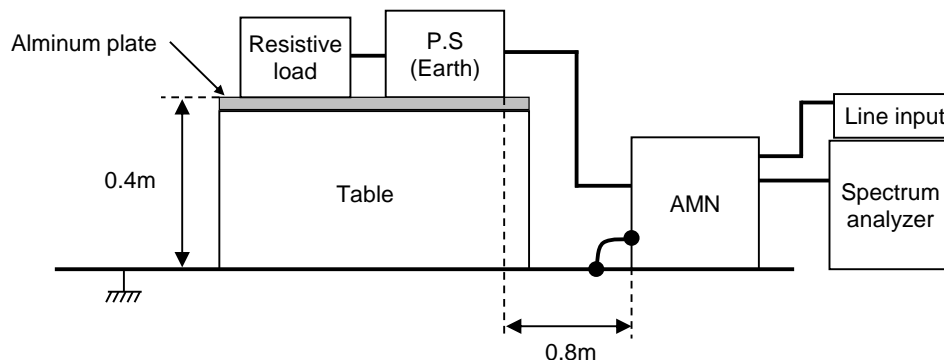
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
6.488	L1	48.7	46.6	73	60	24.3	13.4	Pass	
19.871	L1	46.8	38.6	73	60	26.2	21.4	Pass	
6.487	N	48.9	46.9	73	60	24.1	13.1	Pass	
19.859	N	46.8	38.2	73	60	26.2	21.8	Pass	



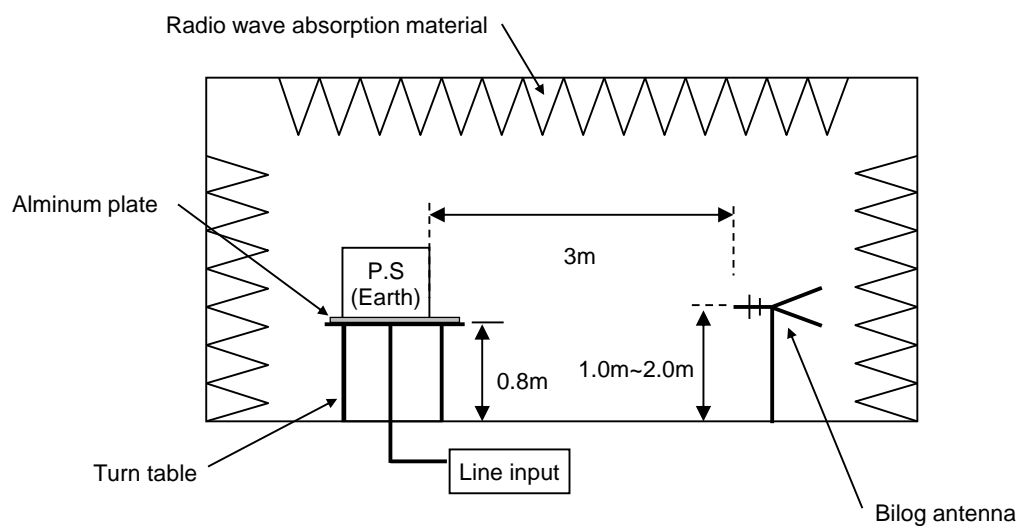
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
46.332	H	Stable	21.1	50	28.9	Pass	100.2	22.3	
46.329	V	Stable	35.7	50	14.3	Pass	100.4	340.2	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

## 1. Line conduction



## 2. Radiated emission



## Conditions

Test : EMI  
Model Name: MHFS6□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

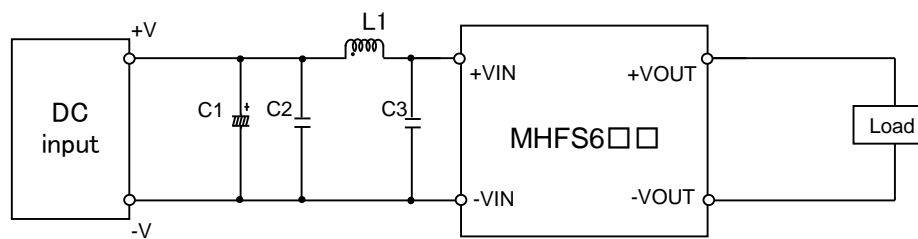


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 $\mu$ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 $\mu$ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 $\mu$ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 $\mu$ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)